May 1996



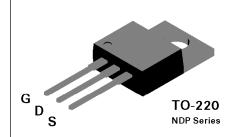
NDP7060 / NDB7060 N-Channel Enhancement Mode Field Effect Transistor

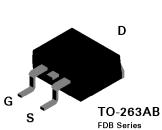
General Description

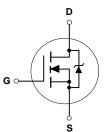
Features

- These N-Channel enhancement mode power field effect transistors are produced using Fairchild's proprietary, high cell density. DMOS technology. This year, high density process is
 T5A, 60V. R_{DS(ON)} = 0.013Ω @ V_{GS}=10V.
 Critical DC electrical parameters specified at elevated
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 Rugged internal source-drain diode can eliminate the need for an external Zener diode transient suppressor.
 - 175°C maximum junction temperature rating.
 - High density cell design for extremely low R_{DS(ON)}.
 - TO-220 and TO-263 (D²PAK) package for both through hole and surface mount applications.

transistors are produced using Fairchild's proprietary, high cell density, DMOS technology. This very high density process is especially tailored to minimize on-state resistance, provide superior switching performance, and withstand high energy pulses in the avalanche and commutation modes. These devices are particularly suited for low voltage applications such as automotive, DC/DC converters, PWM motor controls, and other battery powered circuits where fast switching, low in-line power loss, and resistance to transients are needed.







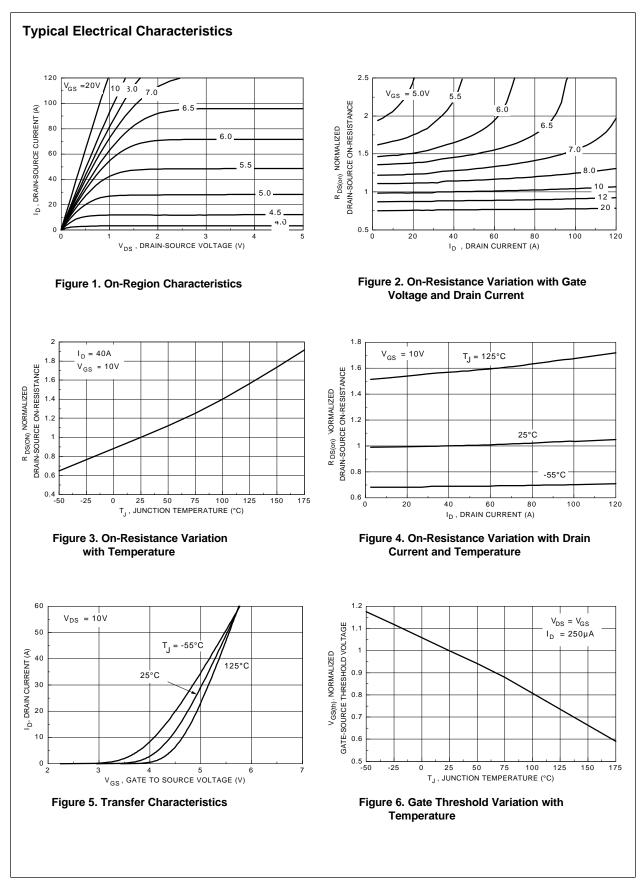
Absolute Maximum Ratings T_c = 25°C unless otherwise noted

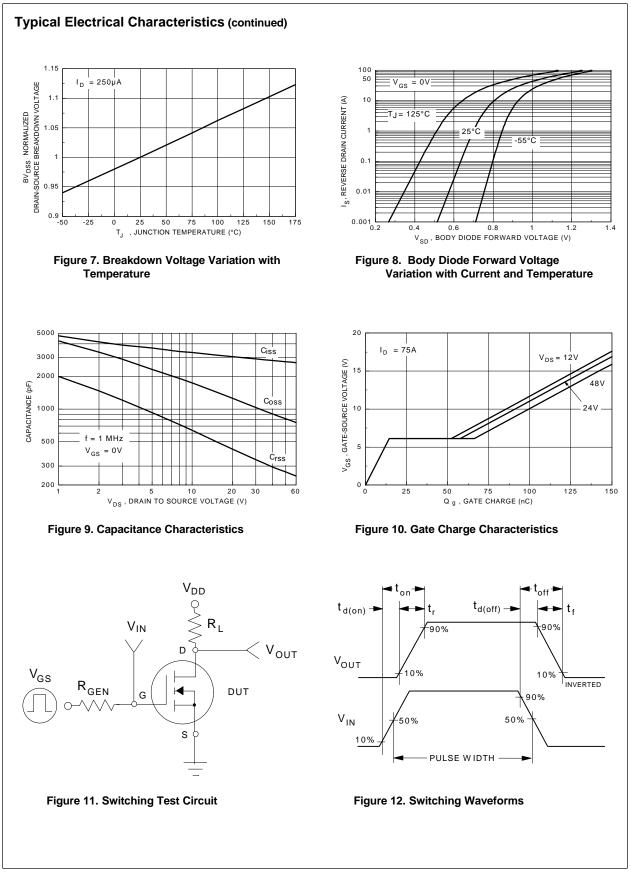
Symbol	Parameter	NDP7060	NDB7060	Units
V _{DSS}	Drain-Source Voltage	60		V
V_{DGR}	Drain-Gate Voltage ($R_{GS} \leq 1 \text{ M}\Omega$)	60		V
V _{GSS}	Gate-Source Voltage - Continuous	±20		V
	- Nonrepetitive ($t_p < 50 \ \mu s$)	± 40		
I _D	Drain Current - Continuous	75		А
	- Pulsed	225		
P _D	Maximum Power Dissipation @ $T_c = 25^{\circ}C$ 150			W
	Derate above 25°C	Derate above 25°C 1		W/°C
T_,,T _{stg}	Operating and Storage Temperature Range	-65 to 17	°C	
TL	Maximum lead temperature for soldering purposes, 1/8" from case for 5 seconds	275		°C

Symbol	Parameter	Conditions		Min	Тур	Max	Units
DRAIN-S	OURCE AVALANCHE RATINGS (Note 1)						
W _{DSS}	Single Pulse Drain-Source Avalanche Energy	$V_{DD} = 25 \text{ V}, \text{ I}_{D} = 75 \text{ A}$				550	mJ
I _{AR}	Maximum Drain-Source Avalanche Curre	ent				75	Α
OFF CH/	ARACTERISTICS						
BV _{DSS}	Drain-Source Breakdown Voltage	$V_{GS} = 0 \text{ V}, I_{D} = 250 \ \mu\text{A}$		60			V
I _{DSS}	Zero Gate Voltage Drain Current	$V_{DS} = 60 \text{ V}, V_{GS} = 0 \text{ V}$	T ₁ = 125°C			250 1	μA mA
	Gate - Body Leakage, Forward	$V_{GS} = 20 \text{ V}, \text{ V}_{DS} = 0 \text{ V}$	1 _J = 120 0			100	nA
	Gate - Body Leakage, Reverse	$V_{GS} = -20 \text{ V}, V_{DS} = 0 \text{ V}$ $V_{GS} = -20 \text{ V}, V_{DS} = 0 \text{ V}$				-100	nA
	RACTERISTICS (Note 1)	GS, DS _					
V _{GS(th)}	Gate Threshold Voltage	$V_{DS} = V_{GS}, I_{D} = 250 \ \mu A$		2	2.8	4	V
			T _{.1} = 125°C	1.4	2.1	3.6	1
R _{DS(ON)}	Static Drain-Source On-Resistance	V _{GS} = 10 V, I _D = 40 A	J		0.01	0.013	Ω
			T _. = 125°C		0.015	0.024	1
I _{D(on)}	On-State Drain Current	V _{GS} = 10 V, V _{DS} = 10 V		75			Α
9 _{FS}	Forward Transconductance	V _{DS} = 10 V, I _D = 37.5 A		15	39		S
DYNAMI	C CHARACTERISTICS	·					
C _{iss}	Input Capacitance	$V_{DS} = 25 \text{ V}, V_{GS} = 0 \text{ V},$ f = 1.0 MHz			2960	3600	pF
C _{oss}	Output Capacitance				1130	1600	pF
C _{rss}	Reverse Transfer Capacitance				380	800	pF
	NG CHARACTERISTICS (Note 1)						
t _{D(on)}	Turn - On Delay Time	$V_{DD} = 30 \text{ V}, \ I_{D} = 75 \text{ A},$			17	30	nS
t,	Turn - On Rise Time	$V_{GS} = 10 \text{ V}, \text{ R}_{GEN} = 5 \Omega$			128	400	nS
t _{D(off)}	Turn - Off Delay Time				54	80	nS
t,	Turn - Off Fall Time				90	200	nS
Q	Total Gate Charge	V _{DS} = 48 V,			100	115	nC
Q _{gs}	Gate-Source Charge	$I_{\rm D}^{\rm US} = 75 \text{A}, V_{\rm GS} = 10 \text{V}$			14.5		nC
Q _{gd}	Gate-Drain Charge				51		nC

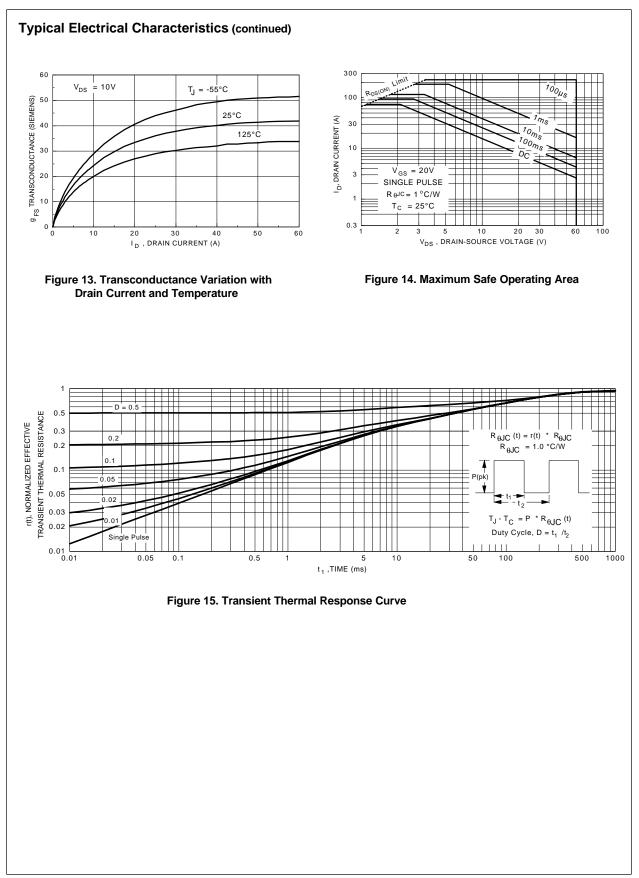
Electric	al Characteristics (T _c = 25°C unless o	therwise noted)					
Symbol	Parameter	Conditions		Min	Тур	Max	Units
DRAIN-S	OURCE DIODE CHARACTERISTICS						•
I _s	Maximum Continuos Drain-Source Diode Forward Current				75	Α	
I _{SM}	Maximum Pulsed Drain-Source Diode Fo	-Source Diode Forward Current				225	Α
V _{SD}	Drain-Source Diode Forward Voltage	$V_{GS} = 0 \text{ V}, \text{ I}_{S} = 37.5 \text{ A} \text{ (Note 1)}$			0.9	1.3	V
			T _J = 125°C		0.84	1.2	
t _r	Reverse Recovery Time	$V_{GS} = 0 \text{ V}, I_{F} = 75 \text{ A}, dI_{F}/dt = 100 \text{ A}$	/µs	40	76	150	ns
l _{rr}	Reverse Recovery Current			2	4.7	10	Α
THERMA	L CHARACTERISTICS						•
R _{θJC}	Thermal Resistance, Junction-to-Case					1	°C/W
R _{ØJA}	Thermal Resistance, Junction-to-Ambient				62.5	°C/W	
Note:						•	

Note: 1. Pulse Test: Pulse Width \leq 300 µs, Duty Cycle \leq 2.0%.





NDP7060.SAM



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